

Example 4: Using Rules to Catch ATE Issues

Finding the Issue

A by-8 probecard is failing on all sites in some touchdowns due to a tester issue. The problem is detected automatically by an offline touchdown-monitoring pre-defined rule. Standard yield monitoring mechanisms fail to discover the issue because wafer yield is still above the acceptable threshold.

Performing the Analysis

The user receives an alert via email minutes after wafer probing is completed. The user views the wafer-map tool and informs the test house. The wafer is re-probed, significant yield is reclaimed and the user is able to view the results of the retest. The tester is investigated to find the root-cause of the problem.

